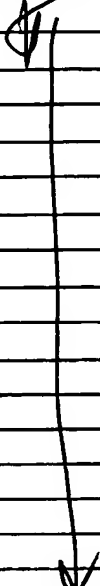




Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Attorney Docket No: U.S. 10/607,613 LAM2P421 Applicant: Kiermasz et al. Filing Date: June 27, 2003 Group: 3723
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Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A	4,606,151	08/1986	Heynacher			
	B	4,850,152	07/1989	Heynacher et al.			
	C	5,575,707	11/1996	Talieh et al.			
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Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
↓	R	EP0920956	06/1999	EPO			x	
	S	JP03259520	11/1991	JPO				x
	T	JP03259520	11/1991	Patent Abstracts of Japan			x	
	U	EP0881039	12/1998	EPO			x	
	V	FR2767735	08/1998	French Patent Office				x

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	W	
	X	
	Y	
	Z	

Examiner:	Date Considered: 12/21/04
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Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Attorney Docket No: U.S. LAM2P421 10/607,613 Applicant: Kiermasz et al. Filing Date: June 27, 2003 Group: 3723
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	K						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	L							
	M							
	N							
	O							
	P							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	
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	T	
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